Deep Learning for Image Recognition and Processing

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Message from the Guest Editors

Deep learning technology has been drawing increasing interest for a wide range of computer vision and image analysis tasks, such as image classification, image segmentation, object detection and so on. A number of applications can be utilized by deep learning technology, such as industrial intelligence, remote sensing image analysis and autonomous driving. However, deep learning technology has faced some challenging problems in various applications, limiting image recognition and processing performance. Some modified deep learning on model-based or module-based strategies cannot cope with the volume of problems, and this must be urgently addressed: for example, how to improve deep learning model accuracy by using a limited sample size, or how to propose an explainable deep learning model to make it precise and reliable. As a result, this Special Issue aims to cover novel strategies on deep learning algorithms for image recognition and processing by using reliable, optimized and hybrid deep learning algorithms in a number of applications.

Special Issue

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Message from the Editor-in-Chief

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